S530 Parametric Test Systems with KTE — Quick and Seamless Integration with Your Existing S400 and S600 Systems
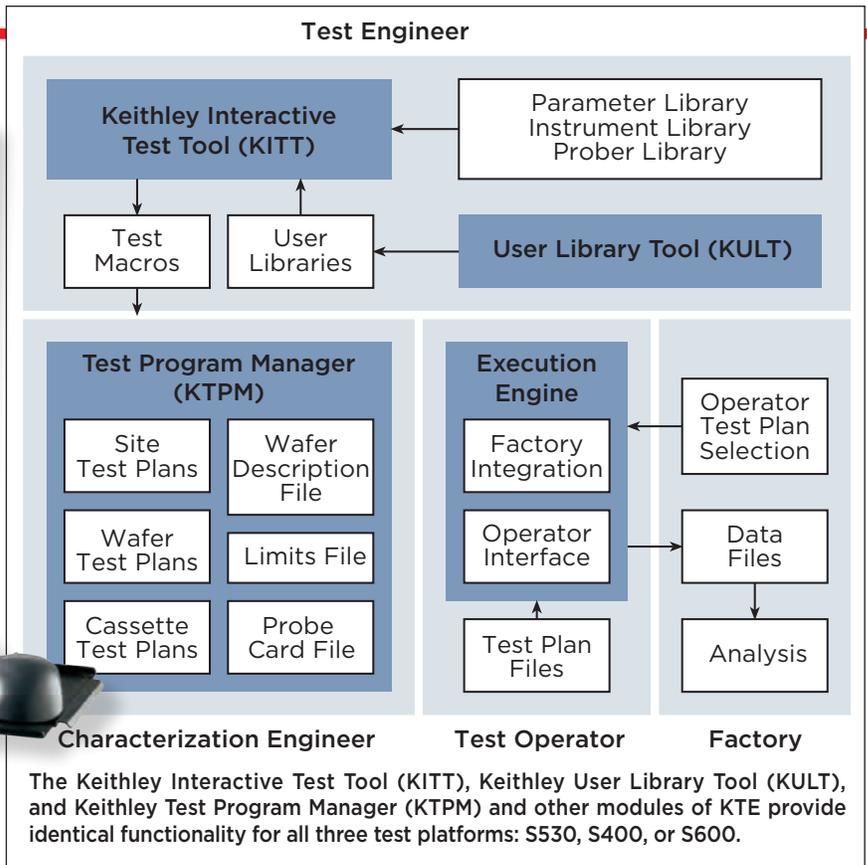

The proven performance of KTE is now integrated with our newest, most cost-effective parametric test system.

- ■ Expand your fab's process control monitoring capacity or replace older systems efficiently and economically
- ■ Enjoy the same fast, flexible test plan development and execution KTE provides for hundreds of facilities around the world on your new test systems
- ■ Eliminate the need for retraining for existing KTE users
- ■ Discover what KTE's proven power and flexibility offer new users
- ■ Port existing measurement libraries to the S530 and adjust easily for measurement correlation
- ■ Use identical test recipes, plans, and other test files across S400, S600, and S530 test systems
- ■ Save time and money by reusing your User Access Point (UAP) code
- ■ Linux OS and standard industrial PC provide stability and ease of maintenance

Keithley Series S400 and Series S600 system users, we've migrated our popular Keithley Test Environment (KTE) to our new Series S530 parametric test systems, our fastest, most cost-effective line of process control monitoring solutions. Now, you can configure both S530 High Voltage and Low Current test systems with the same test creation and execution environment refined and proven at hundreds of customer facilities worldwide.

If you're using Keithley Series S400 and/or S600 systems already, KTE V5.3 makes integrating S530s into your test floor quick and simple:

- ■ High platform-to-platform compatibility lets you **use the same test recipes and test plans for all your Keithley automated parametric test systems.** That not only shortens the learning curve for your test engineers and operators working with multiple systems but offers a smooth migration path to protect your test development investment when adding new high speed systems to your test floor or replacing older ones.
- ■ The commands used in the KTE linear parametric test library (LPTLIB) and parametric test library (PARLIB) are **compatible with all three test platforms**.
- ■ You can **continue working with the familiar user libraries** you've developed for Series S400/S600 systems over the years after recompiling and rebuilding them for use with the S530. Typically, only minimal debugging is required.
- ■ KTE V5.3 **simplifies creating new UAP source code** for conditional test sequencing and customizing the flow of your system operation. Simply reuse UAP source code from your S400 or S600, and apply it to the S530 with minimal adjustments.
- ■ KTE's Keithley Interactive Test Tool (KITT), Keithley User Library Tool (KULT), Keithley Test Program Manager (KTPM), and the other KTE tools **provide identical functionality for all three system platforms**.

A GREATER MEASURE OF CONFIDENCE

KEITHLEY

Test Engineer

| Keithley Interactive Test Tool (KITT) | | Parameter Library Instrument Library Prober Library |

| Test Macros | User Libraries | User Library Tool (KULT) |

Test Program Manager (KTPM)

Site Test Plans	Wafer Description File
Wafer Test Plans	Limits File
Cassette Test Plans	Probe Card File

Execution Engine

Factory Integration	Operator Test Plan Selection
Operator Interface	Data Files
Test Plan Files	Analysis

Characterization Engineer   Test Operator   Factory

The Keithley Interactive Test Tool (KITT), Keithley User Library Tool (KULT), and Keithley Test Program Manager (KTPM) and other modules of KTE provide identical functionality for all three test platforms: S530, S400, or S600.

The brand new system with three decades of test expertise behind it

By extending the KTE test development and execution environment to S530 systems, we're bringing the advantages of Keithley's three decades of field experience in parametric test code development together with the fastest, most advanced system hardware available in the market. S530 instrumentation provides the speed and wide measurement range that parametric test applications like process control monitoring demand.

S530 Parametric Test Systems running KTE V5.3 can address all of the I-V and C-V measurements required in process control monitoring, process reliability monitoring, and device characterization. S530 systems are optimized for use in production parametric test environments that must accommodate a broad mix of products or wherever wide application flexibility and fast test plan development are critical. For details on the S530 systems, see our online brochure and datasheet at www.keithley.com.

Build tests and sequences quickly and flexibly

When using KTE for the S530, you can quickly create individual electrical tests at the subsite level by drawing on libraries of tests, then defining parameters and connections. To ensure maximum electrical test flexibility, KTE also allows you to create custom parametric tests using the Keithley User Library Tool (KULT), a powerful tool for creating, editing, and compiling user-defined test libraries.

High reliability and high speed

We've optimized KTE V5.3 for the S530 for long-term reliability and speed in high throughput production test. It's designed to run on a Linux operating system on a standard industrial PC to ensure lasting stability and ease of maintenance.

Platform-to-platform compatibility ensures ongoing ROI

Keithley has continually enhanced and maintained the KTE test development and execution environment and has proven its effectiveness at hundreds of customer sites worldwide. Our continuing commitment to maintaining software compatibility between test platforms assures you of a smoother migration path to Keithley's latest high speed test systems. KTE has the flexibility to change with the industry's changing test needs, stretching your capital investment further and improving your ROI.

Want to learn more?

For more information on the latest enhancements to our Series S530 parametric test systems, download our new brochure, data sheet, high voltage testing white paper, and application note, which are all available online at www.keithley.com, or contact your Keithley sales representative.

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